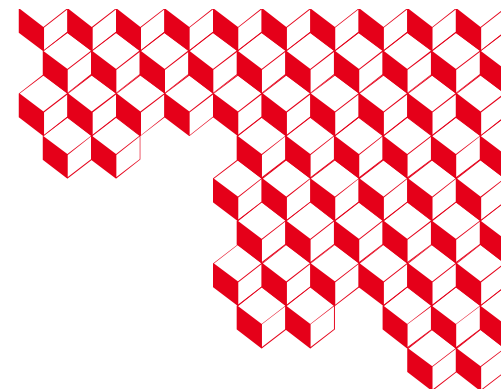




Towards less than 10 mg/Wp silver consumption in HJT modules with ECA based interconnection

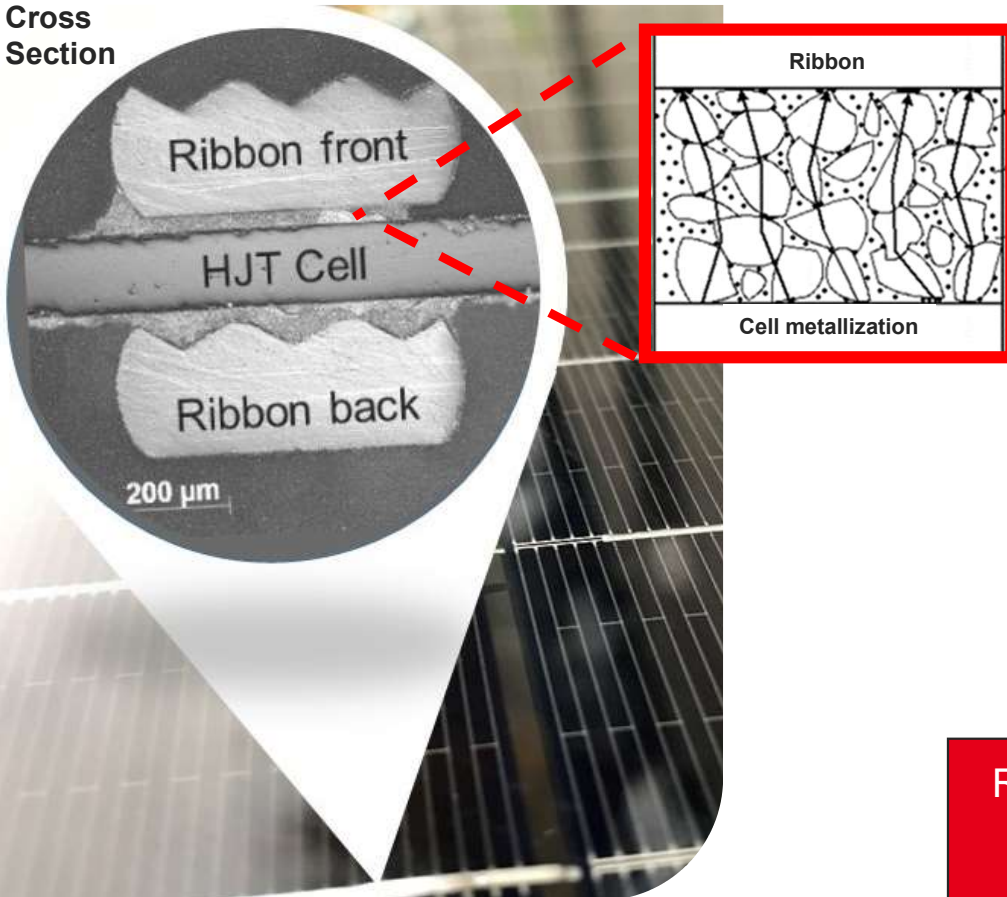
Rémi Monna, Gustavo Rodrigues Lopes, Nathalie Ronayette-Lamoine, Laurent Fonteneau,
Anne-Sophie Ozanne, Jules Clerjon, Didier Therme, Johann Jourdan, Bertrand Hladys



Cell interconnection for HJT cells made with Electrically Conductive Adhesives (ECA)

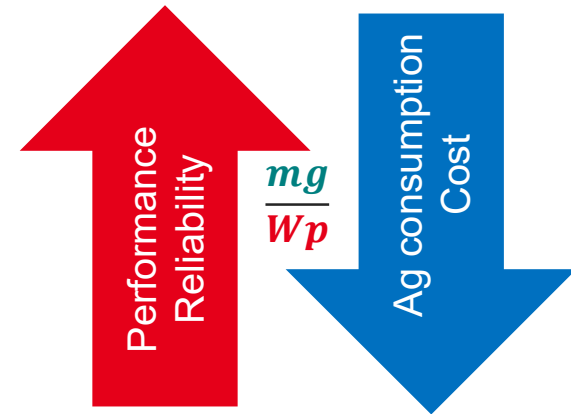


Cross
Section



- ✓ Lead and Bismuth free technology
- ✓ Low T° process and wide window (80 - 200°C)
- ✓ Compatibility with temperature sensitive cells like HJT and Si-Perovskite tandem cells

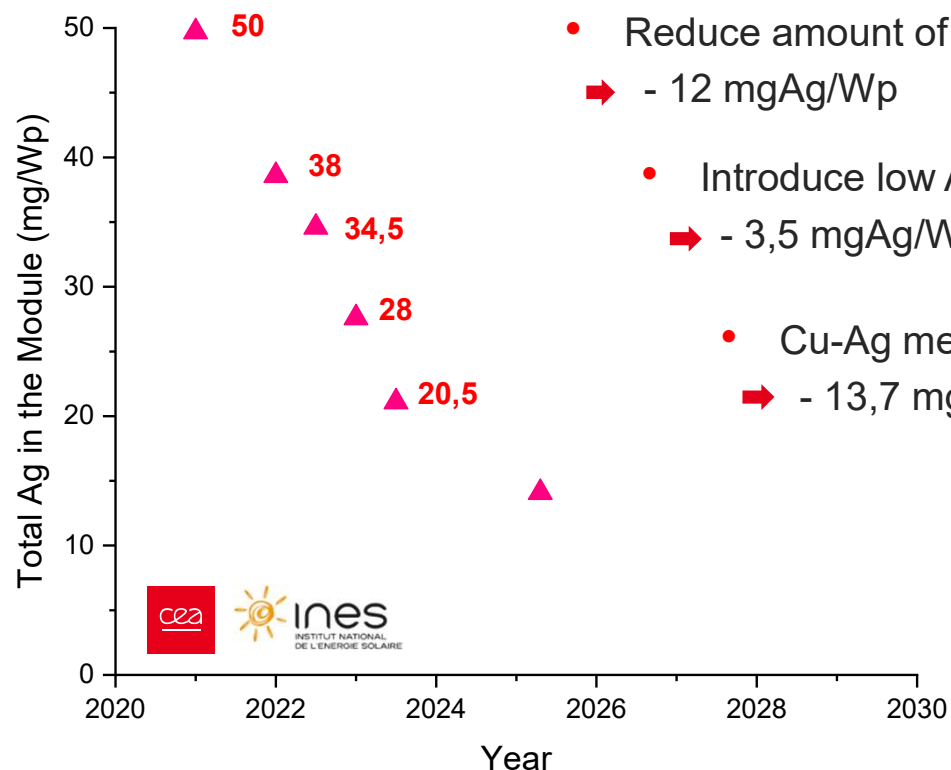
Continue to
reduce Ag
consumption
while maintaining
**PERFORMANCE
and
RELIABILITY**



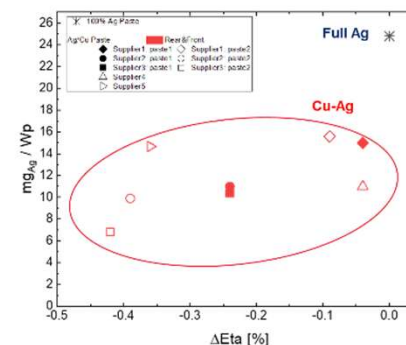
Radical reduction of silver is a must for TW
scale manufacturing in PV
Our target < **3 mg/Wp by 2030**

Ag reduction in the module with ECA interconnection

❖ From 50 mg/Wp to 14 mg/Wp in less than 5 years

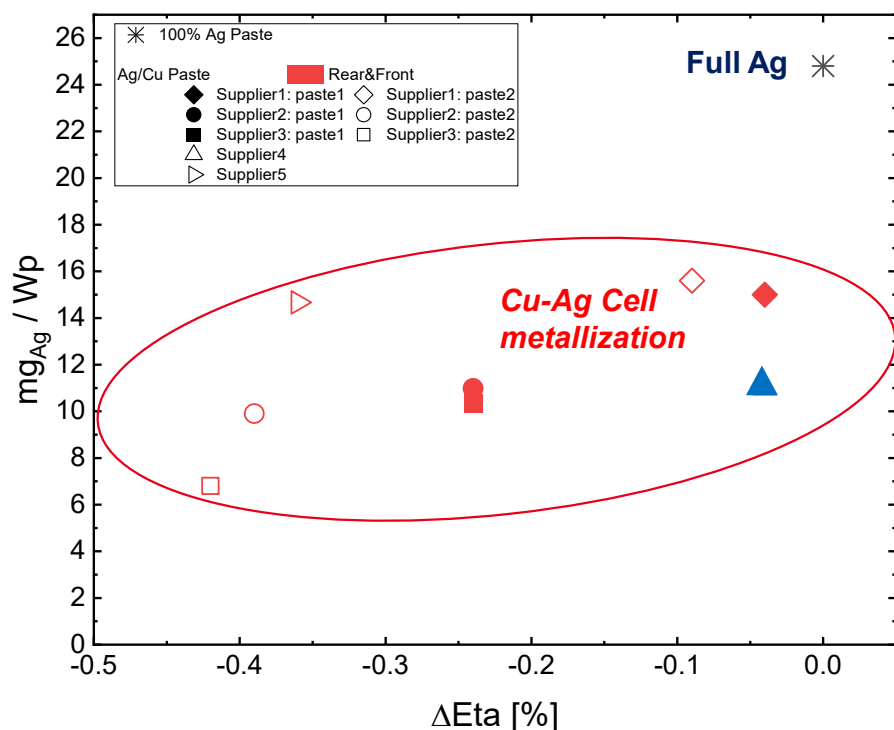


- Reduce amount of deposited ECA
➡ - 12 mgAg/Wp
- Introduce low Ag content ECAs
➡ - 3,5 mgAg/Wp
- Cu-Ag metallization on HJT Cells
➡ - 13,7 mgAg/Wp



Ag reduction in the module with ECA interconnection

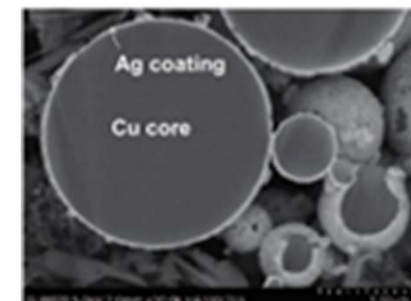
❖ From 50 mg/Wp to 14 mg/Wp in less than 5 years



A.Lanterne & al : Copper-based Metallization Approaches for Drastic Reduction of Silver Content in Heterojunction Solar Cells – PVSEC 2024

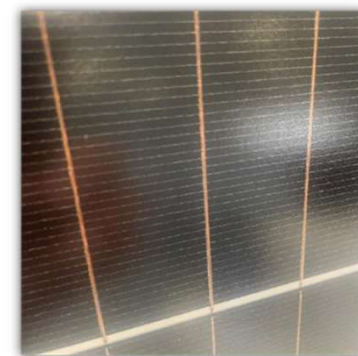
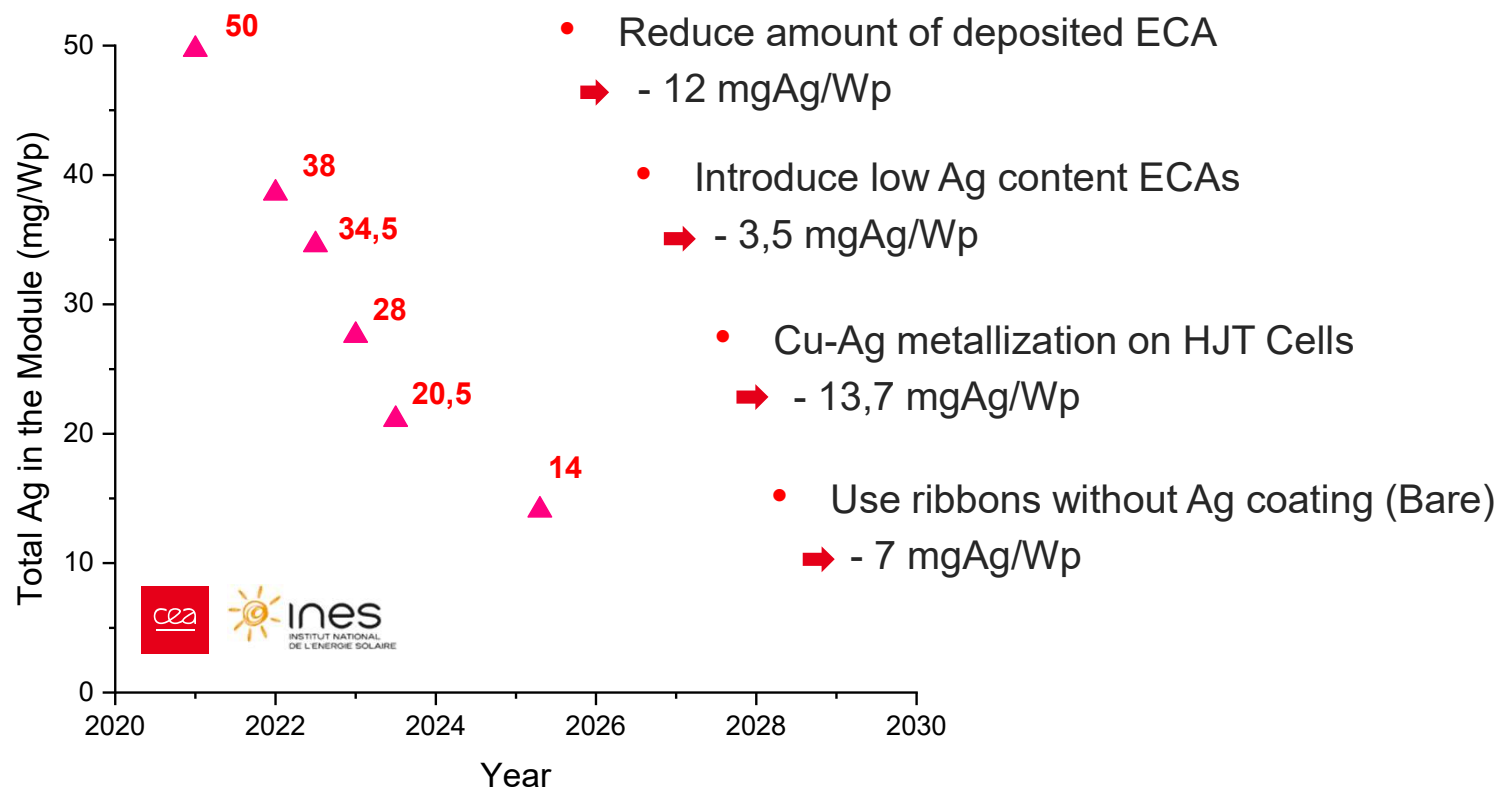
✓ Cu-Ag Cell metallization

- Cu core particles / Ag coating
- 11 mgAg/Wp give a loss of 0.05 % absolute efficiency
- 7 mgAg/Wp is reachable but with a loss of 0.4 % of absolute efficiency with Cu-Ag Paste



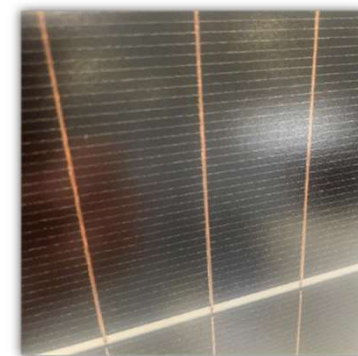
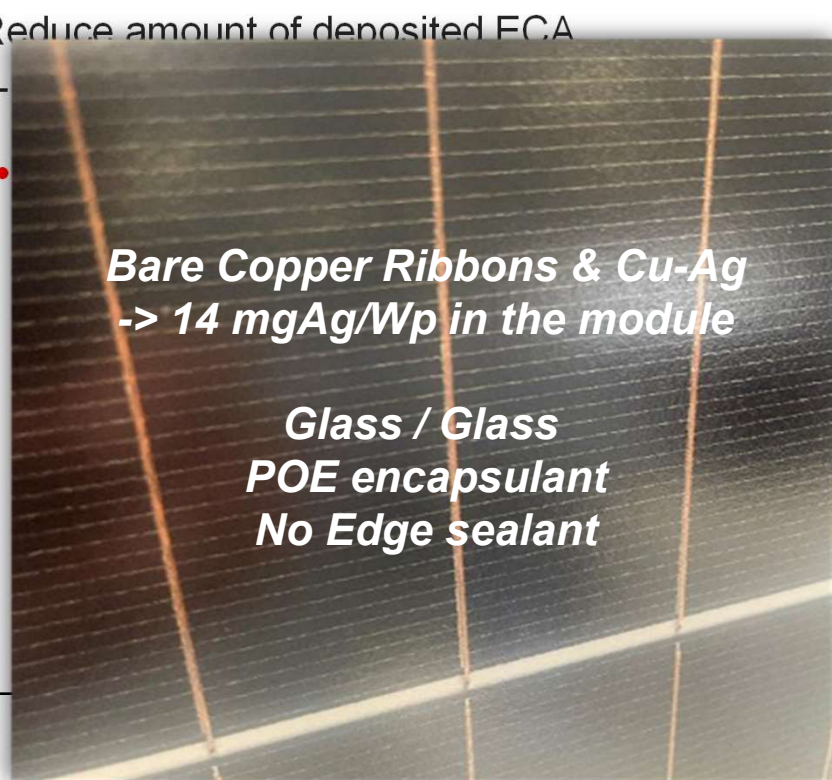
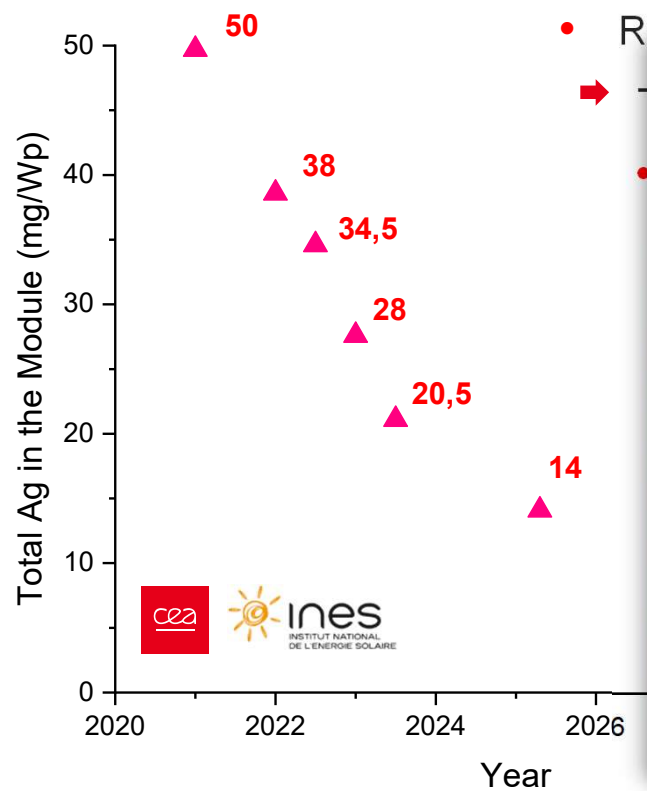
Ag reduction in the module with ECA interconnection

❖ *From 50 mg/Wp to 14 mg/Wp in less than 5 years*

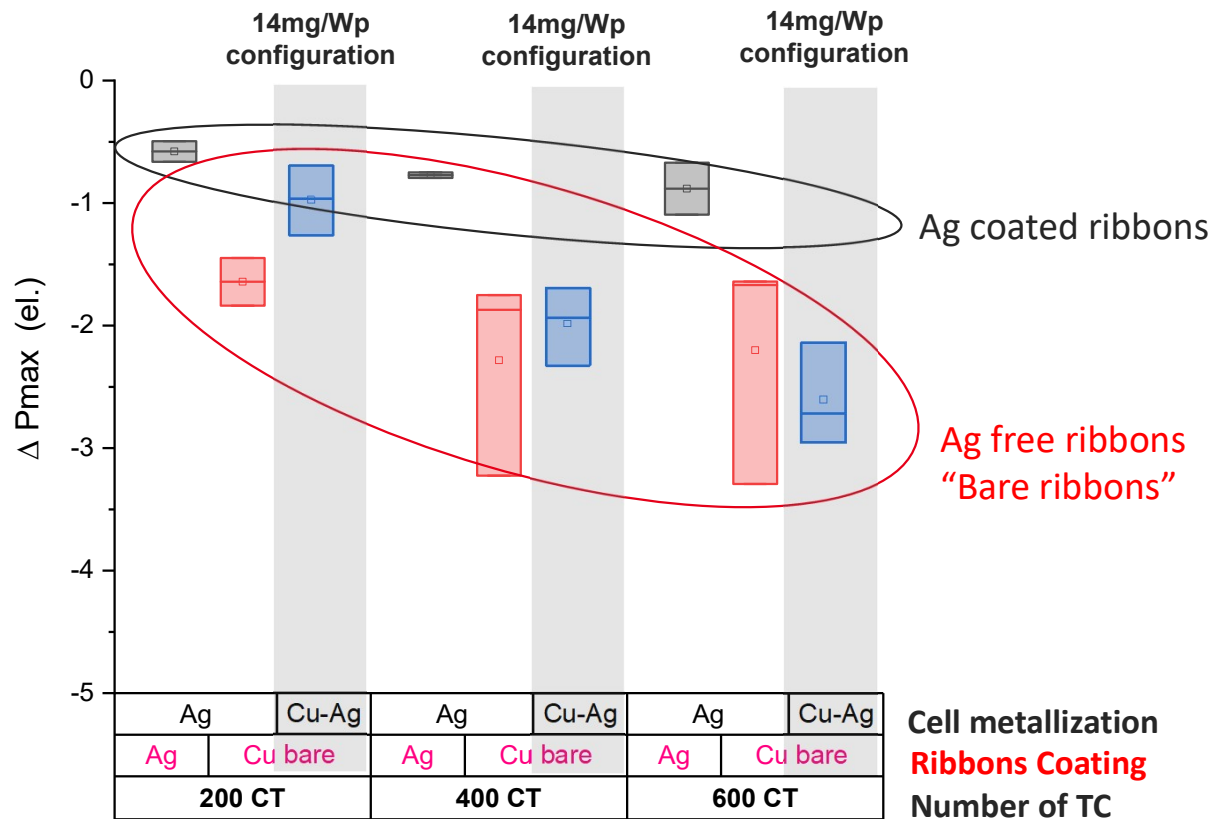


Ag reduction in the module with ECA interconnection

❖ From 50 mg/Wp to 14 mg/Wp in less than 5 years



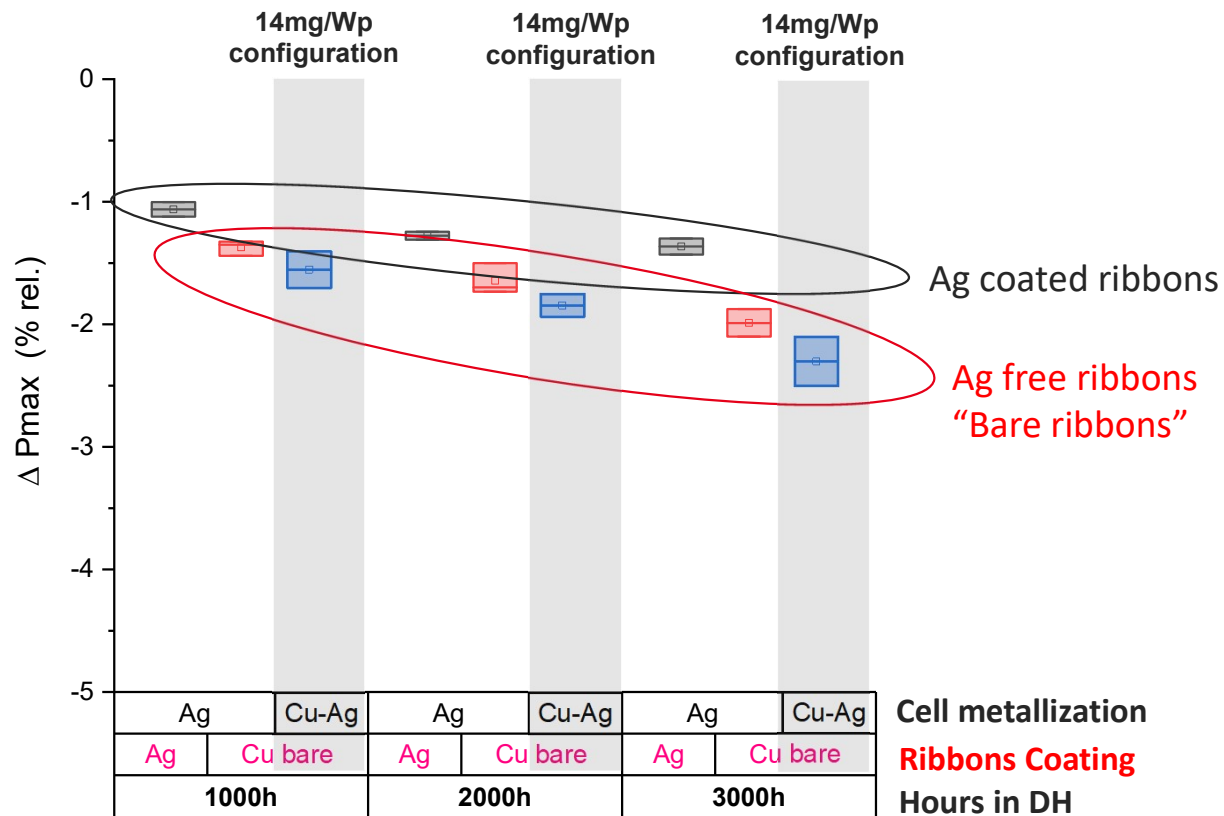
TC Ageing results



- ✓ The degradation is more pronounced on the modules with "bare ribbons"
- ✓ No difference observed between Ag and Cu-Ag Cell metallization
- ✓ Less than 3 % degradation after 600 TC
- ✓ Degradation only due to FF
 - No I_{sc} & V_{oc} change

R.Monna & Al , Use of Cu ribbons and Cu-Ag HJT cell metallization on ECA based interconnection for PV modules, Solar Energy Materials and Solar Cells, Volume 287, 1 August 2025, 113594

DH ageing results



- ✓ The degradation is more pronounced on the modules with "bare ribbons"
- ✓ Cu-Ag Cell metallization seems to degrade a little bit more
- ✓ Less than 3 % degradation after 3000 h DH
- ✓ Degradation mainly due to FF
 - Minor V_{oc} degradation

Combining Cu-Ag metallized cells with bare Cu ribbons allows to reach a **total Ag consumption in the MODULE of 14 mg/Wp** with a degradation of less than 3 % after 3000h DH and 600 TC

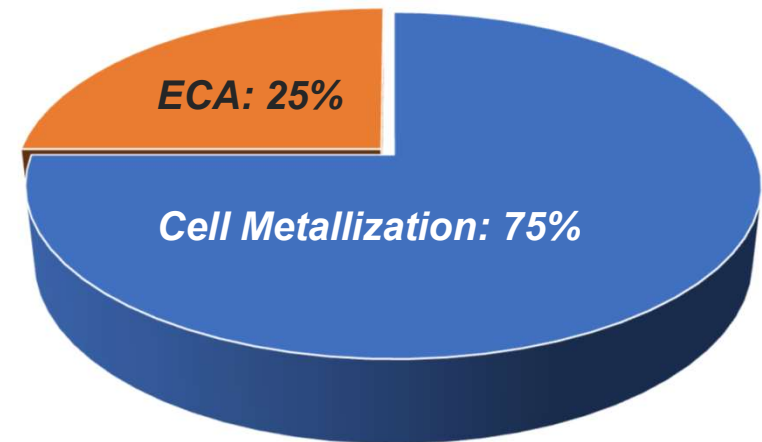
How can we decrease more the Ag consumption ?



- ✓ ECA represent 25 % of the Ag consumption
 - Reduce the deposited weight -> ECA dots or pads
 - Reduce the amount of Silver in the ECA

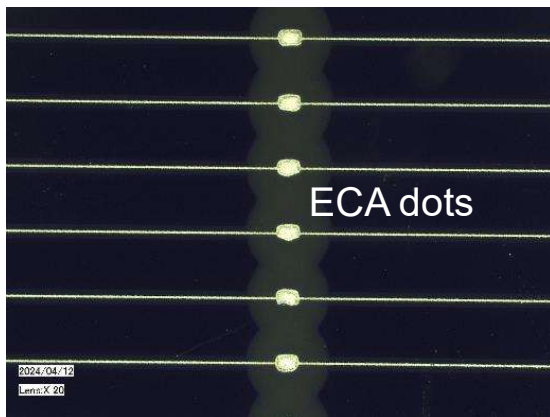
- ✓ The cell represent more than 75%
 - Go to full Cu Cell metallization
 - Introduce ZBB cells

❖ *Ag consumption in the Module*

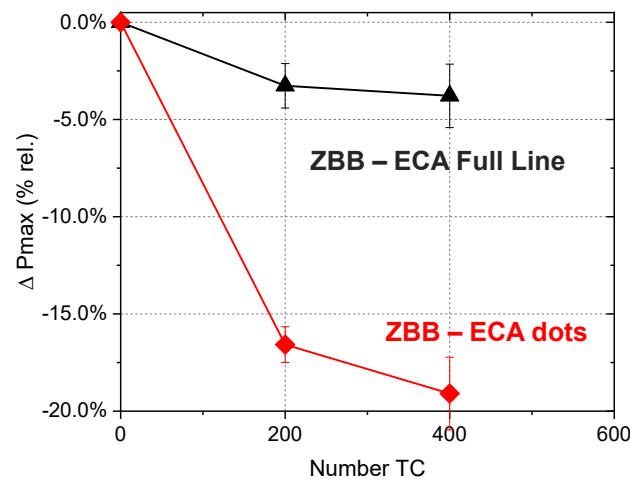


To ZBB interconnection

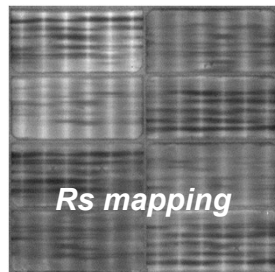
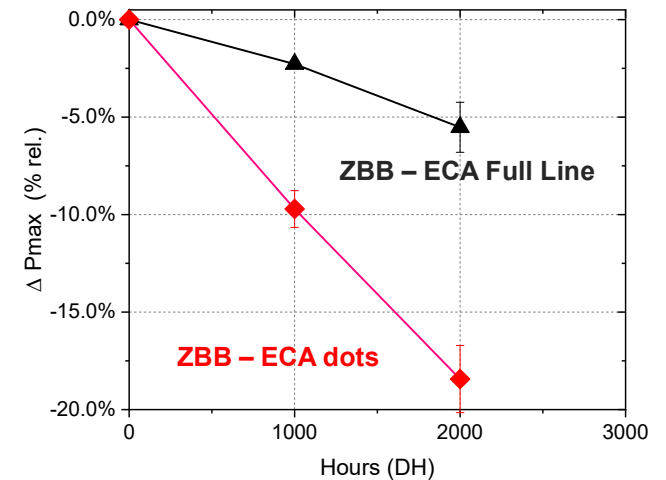
- ✓ Possibility to gain 1.1 mg/Wp with ZBB cells (Cu-Ag metallization)
- ✓ Possibility to gain 1.9 mg/Wp with ECA dots deposition



❖ *TC ageing results*



❖ *DH ageing results*

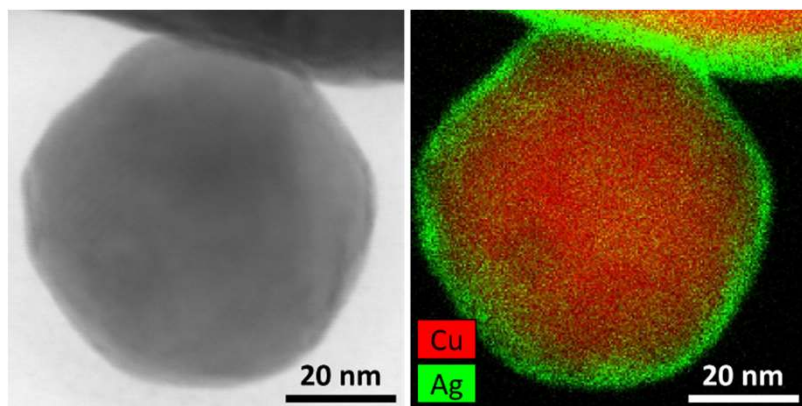


Significant power decrease (> 15%) with ECA dots on ZBB cells after thermal cycling and damp heat

- ✓ Issue with pad alignment that increases series resistance

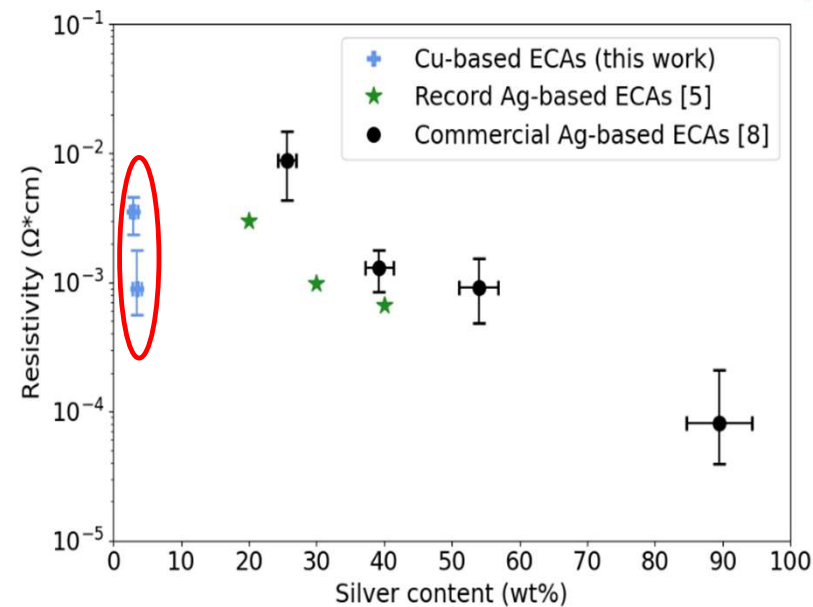
To Cu-based ECAs

❖ Home-made Cu-Ag nanoparticles *



- ✓ Core-Shell copper-silver particles
- ✓ $T_{\text{onset}} = 178 \pm 2 \text{ }^{\circ}\text{C}$

* Nathalie Ronayette & Al, Reduction of silver content in Electrically Conductive Adhesives for low-temperature interconnection of solar cells, Solar Energy Materials and Solar Cells, Volume 292, 15 October 2025, 113762



- ✓ Resistivities from 3.5×10^{-3} to $9.0 \times 10^{-4} \text{ } \Omega \cdot \text{cm}$ comparable to commercial ECAs
- ✓ Ag content < 10 wt%

2.5 mgAg/Wp gain (ECA)
Ageing tests on progress

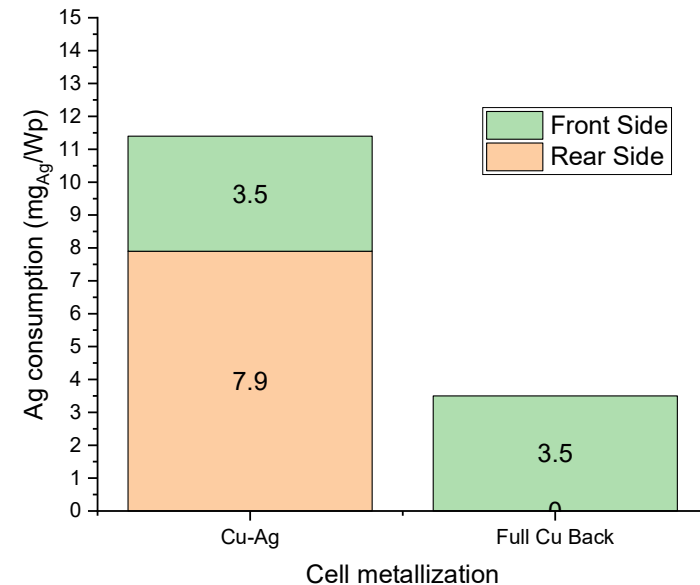
Rear Side Full Cu metallization as a strategy towards lower Ag consumption

❖ Full Copper on the Backside

- ✓ Front Side: Cu-Ag (~40 wt% Ag) screen-printing metallization
- ✓ Rear Side: Full Cu screen-printing metallization
 - Larger screen-opening for optimal results
 - Heating press used for Cu paste annealing

7 mgAg/Wp in the module with
BARE Cu ribbons

❖ Ag consumption on the Cells

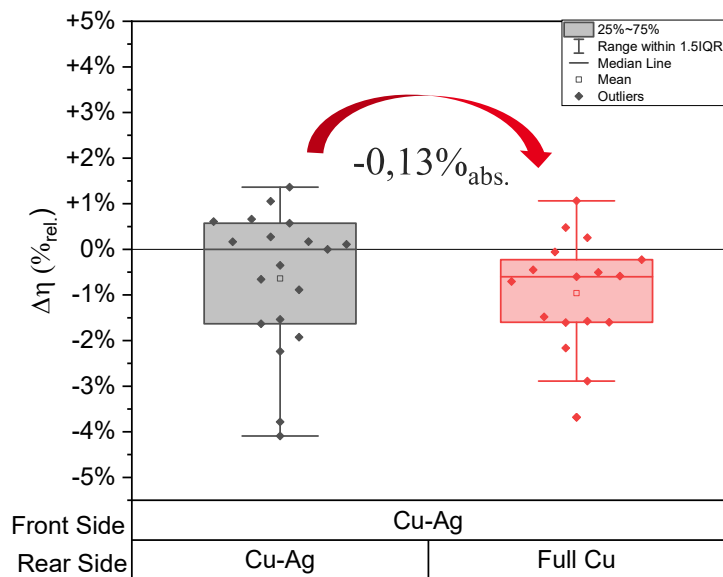


✓ 3.5 mgAg/Wp on the cell

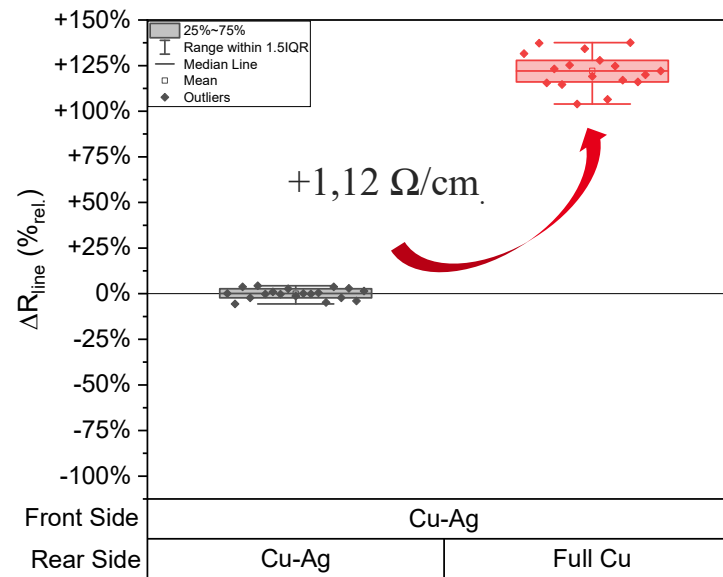
Rear Side Full Cu metallization as a strategy towards lower Ag consumption



Cell Efficiency



R_{line} – Rear Side



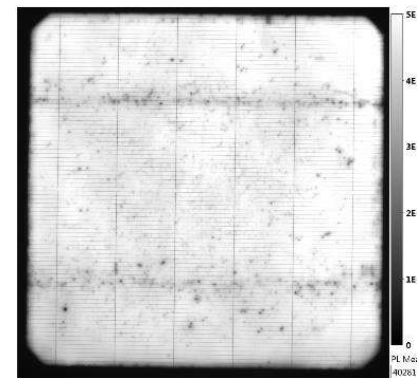
- ✓ Efficiency loss reduced to 0.13 % absolute / Cu-Ag metallization
- ✓ Increase of the line resistance on the backside

TCO as a barrier layer against Cu diffusion

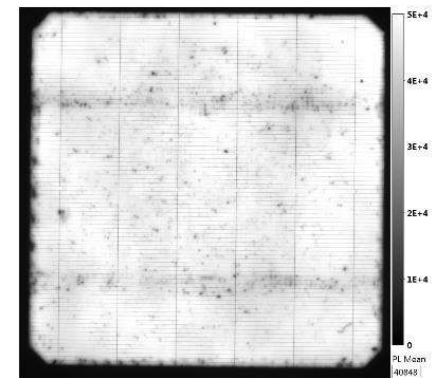


❖ PL images

- ✓ TCOs are well documented as a relatively effective barrier to Cu diffusion at moderate temperatures ($\leq 300^\circ\text{C}$)
- ✓ No lifetime degradation observed after metallization annealing
- ✓ The long-term stability still needs to be investigated at the module level



Cu-Ag Front & Back

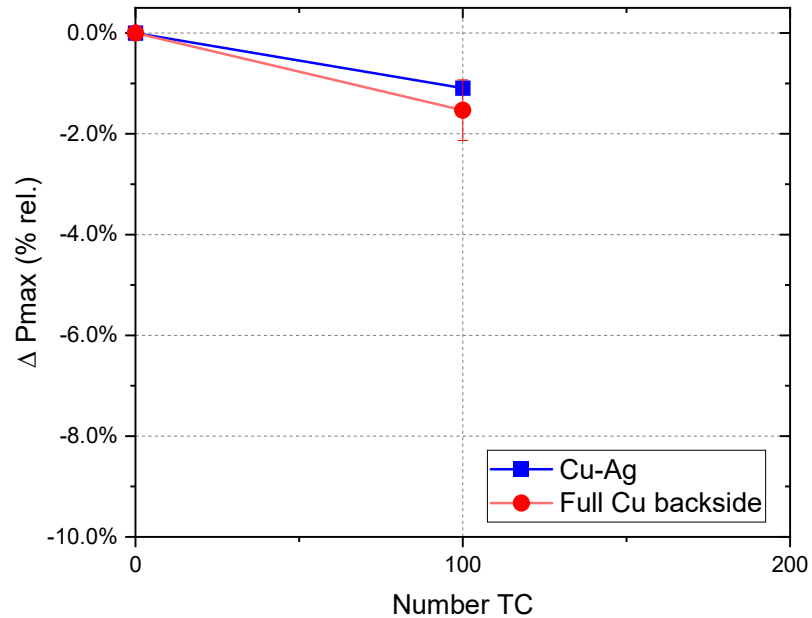


Full Cu Back

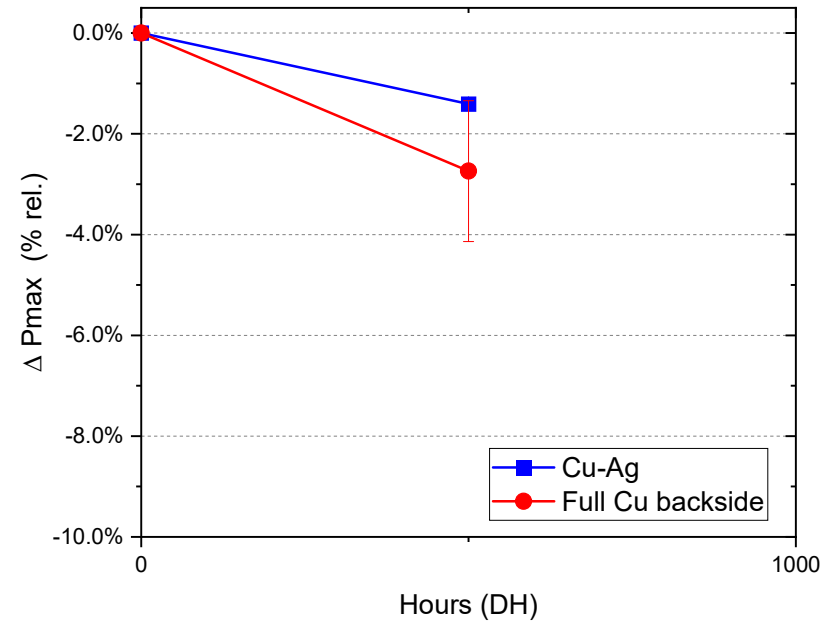
Rear Side Full Cu metallization as a strategy towards lower Ag consumption



❖ *TC ageing results on modules*

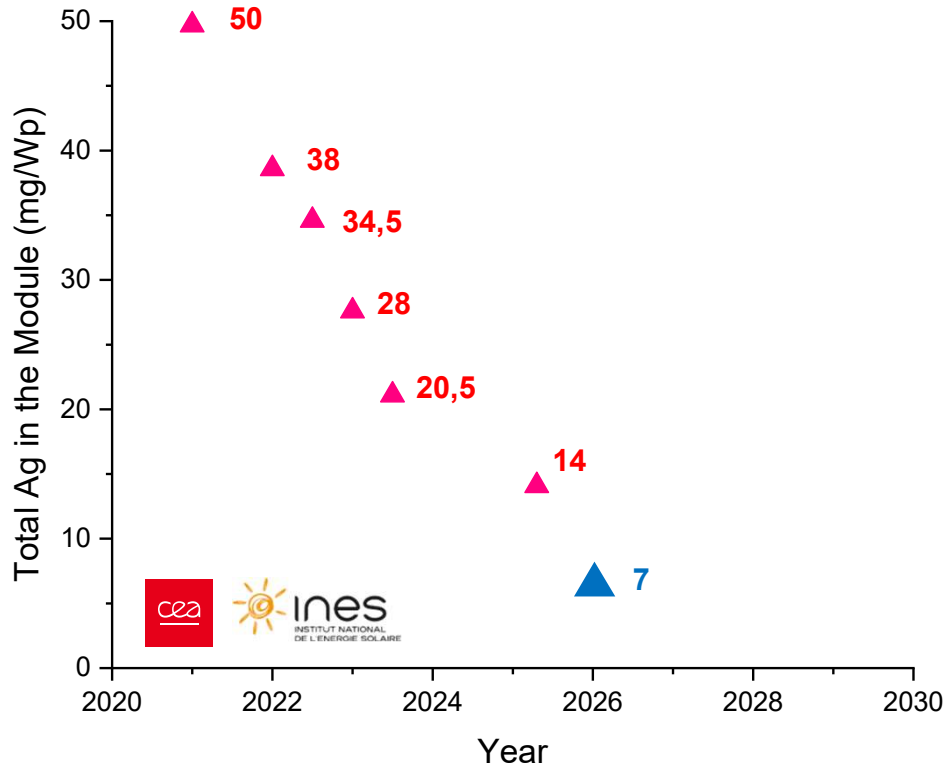


❖ *DH ageing results on modules*



- ✓ Good results on CT ageing compared to our reference Cu-Ag
- ✓ Slightly elevated degradation after 500 hours of DH

Conclusion of the study

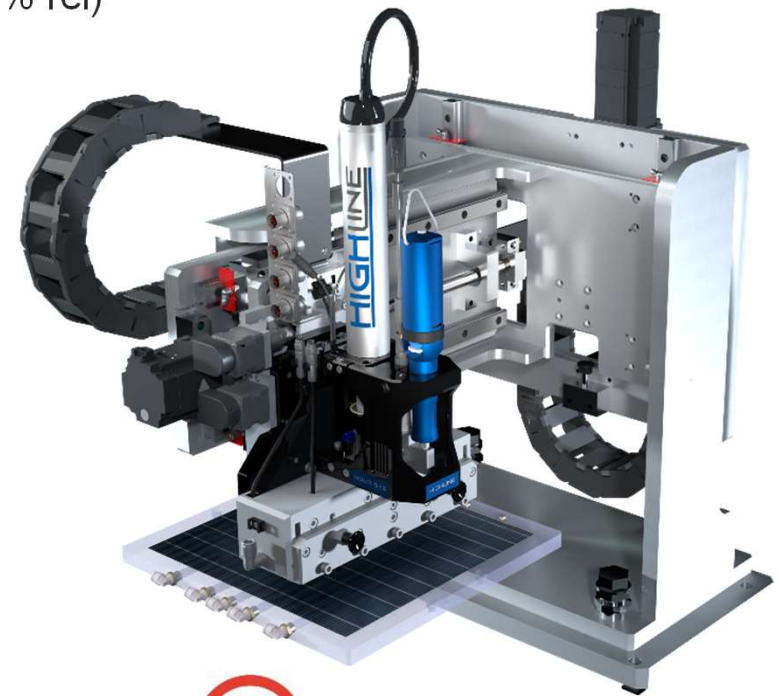


- ✓ **14 mgAg/Wp** reached **on module** by interconnecting Cu-Ag metallized HJT cells with bare Cu ribbons and ECA
 - Less than 3 % degradation after 600 TC and after 3000 h DH (3x IEC passed)
- ✓ Significant power losses with ECA dots after thermal cycling and damp heat
 - Reducing silver consumption in the ECA should rather be achieved through a decrease in the Ag concentration in the ECA
- ✓ HJT cells with Full Cu metallization on the Backside
 - **7 mg/Wp silver consumption in the module**
 - Encouraging initial aging tests; Some issues in DH which has to be solved

Upcoming developments

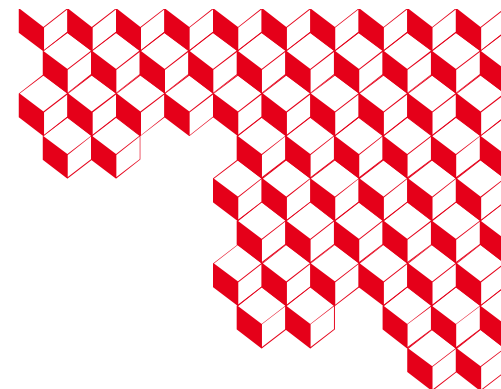
- ✓ Make reliable HJT modules with full Cu metallized Cells – Edge Sealant will probably be necessary
- ✓ Front and Back 100 % Cu Cell metallization to obtain a consumption of 3 mg/Wp in the module
- ✓ Reduce electrical losses with Cu pastes and bare Cu ribbons (-2 % rel)
- ✓ Interconnexion with Wires (needs mechanical strengthening)

- ✓ **Novel ECA deposition** – Cell stringing up to ½ G12 Cells
 - ✓ Put down ECA with the « Highline » dispensing head
 - Reduces ECA consumption: More than 15% reduction in material usage.
 - Increases throughput: More than 20% increase in throughput.
 - Versatility: Capable of handling various materials incl. emerging technologies
 - No contact with the cell -> Advantageous for Tandem Cells



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Thank you



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